## Application/Control No. Applicant(s)/Patent Under Reexamination 10/605,791 CHEN ET AL. **Notice of References Cited** Art Unit Examiner Page 1 of 1 Amare Mengistu 2629 **U.S. PATENT DOCUMENTS** Date **Document Number** Classification \* Name Country Code-Number-Kind Code MM-YYYY \* US-2006/0055645 A1 03-2006 Kim, Jong-Seon 345/087 Α \* 09-2003 Kim et al. US-6,618,101 B1 349/54 В US-C US-D US-Ε US-US-G US-Н US-US-US-K US-US-**FOREIGN PATENT DOCUMENTS** Date **Document Number** Classification Country Name Country Code-Number-Kind Code MM-YYYY N 0 Р Q R S **NON-PATENT DOCUMENTS** \* Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧ W

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